

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/054,581	ROCKWELL ET AL.	
Examiner	Art Unit	
Christina Y. Leung	2633	_

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NO)
	DATE	EXMR
Updated EAST search (see search history)	7/25/2005	æ
IEEE database search (keywords included: "tunable laser")	7/25/2005	ce
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